特別講義

明治大学 国際交流基金事業
「研究者交流支援制度」

Phase Analysis for Optical Measurements

2025年 7月17日 木 10:50～12:30

明治大学 生田キャンパス 中央校舎0608教室

講演詳細（使用言語は英語です）

This lecture will cover modern computational approaches to phase retrieval in optical metrology. Topics include fringe pattern analysis, variational image decomposition, and real-world quantitative phase imaging and interferometry applications.

Artificial Intelligence for Optical Measurements

2025年 7月31日 木 10:50～12:30

明治大学 生田キャンパス 中央校舎0608教室

講演詳細（使用言語は英語です）

In this talk, Dr. Cywińska will explore how AI, including deep learning and neural networks, is revolutionizing the analysis of optical data. She will showcase how data-driven models enhance resolution, robustness, and speed in applications ranging from biomedical to technical imaging.

講師紹介　Maria Cywińska 博士

Dr. Maria Cywińska is an Assistant Professor at the Institute of Micromechanics and Photonics, Faculty of Mechatronics, Warsaw University of Technology. Her research bridges advanced optical metrology and artificial intelligence, with a focus on full-field phase analysis using variational and deep learning techniques. She has contributed to numerous national and international projects in computational imaging, quantitative phase microscopy, and ptychographic reconstruction. Dr. Cywińska has been invited to present her work at leading international conferences and has completed multiple research stays in renowned laboratories worldwide.

主催：明治大学　理工学部専任准教授／有川 秀一

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参加無料